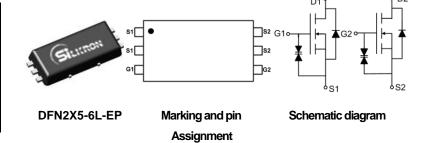


Main Product Characteristics:

V _{DSS}	20V
R _{DS} (on)	14.5mohm (typ.)
I _D	8.5A



Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	8.5 ①	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	75 ①	А
I _{DM}	Pulsed Drain Current ②	34	
V _{GS}	Gate to source voltage	±10	V
P _D @TC = 25°C	Power Dissipation ③	1.3	W
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C





Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

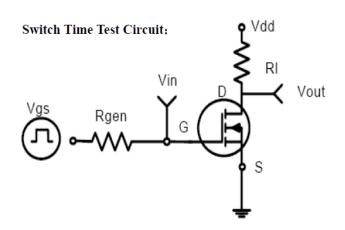
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage		_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
			14.5	17.5		$V_{GS} = 4.5V, I_D = 4A$
Б	Static Drain-to-Source on-resistance	_	15.2	18.5	mΩ	$V_{GS}=4V,I_{D}=4A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	17.3	20	11177	V _{GS} = 3.1V,I _D = 4A
		_	20.3	27.5		$V_{GS} = 2.5V, I_D = 4A$
$V_{GS(th)}$	Gate threshold voltage	0.5	_	1.45	V	$V_{DS} = V_{GS}$, $I_D = 1mA$
I _{DSS}	Drain-to-Source leakage current	_	_	1	μA	V _{DS} =20V,V _{GS} = 0V
I _{GSS} Gate-to-Source forward leakage	Cata to Source forward looked	_	_	10	μΑ	V _{GS} =10V
	Gate-to-Source forward leakage	_	_	-10		V _{GS} = -10V
Qg	Total gate charge	_	8	_		I _D =6A,
Q _{gs}	Gate-to-Source charge	_	1.5	_	nC	V _{DS} =10V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	2	_		V _{GS} =4.5V
t _{d(on)}	Turn-on delay time	_	20	_		V _{DD} =10V ,
t _r	Rise time	_	50	_	nS	$I_D = 1A$,
t _{d(off)}	Turn-Off delay time	_	64	_	115	RG=10 Ω ,
t _f	Fall time	_	40	_		V _{GS} =4.5V
C _{iss}	Input capacitance	_	650	_		V _{GS} = 0V
C _{oss}	Output capacitance		170	_	pF	V _{DS} =10V
C _{rss}	Reverse transfer capacitance	_	150	_		f = 1MHz

Source-Drain Ratings and Characteristics

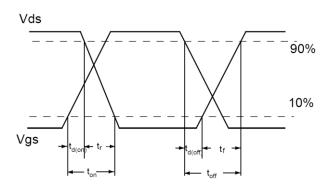
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	_	_	8.5	А	MOSFET symbo showing the
I _{sm}	Pulsed Source Current	_	_	34	А	integral reverse p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.7	1.3	V	Is=1.5A, Vgs=0V



Test circuits and Waveforms



Switching time waveform:



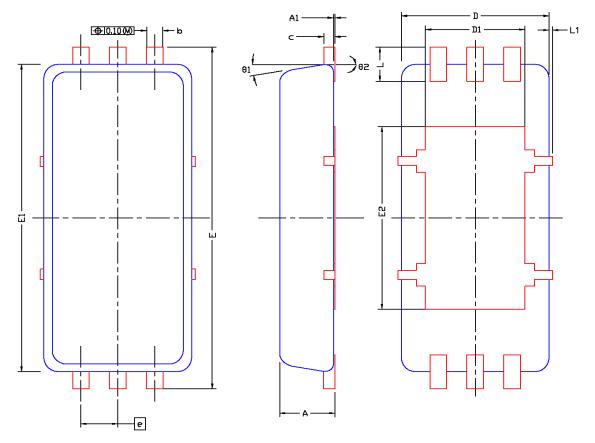
Notes:

- ①The maximum current rating is limited by bond-wires.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.



Mechanical Data:

DFN2X5-6L-EP PACKAGE OUTLINE DIMENSION:



Dim.	Millimeters			Inches			
DIIII.	MIN	NOM	MAX	MIN	NOM	MAX	
A	0.70	0.75	0.80	0.028	0.030	0.0315	
A1	0.00		0.05	0.000		0.002	
b	0.20	0. 225	0.30	0.008	0.009	0.012	
С	0.10	0. 152	0.20	0.004	0.006	0.008	
D		2.00 BSC		0.079 BSC			
D1	1.30	1.35	1.55	0.051	0.053	0.061	
Е	5.00 BSC			0. 197 BSC			
E1		4.50 BSC		0. 177 BSC			
E2	2.60	2.67	2.95	0. 102	0. 105	0.116	
е		0.50 BSC			0.020 BSC	,	
L	0.40	0.50	0.60	0.016	0.0197	0.0236	
L1	0		0.100	0		0.004	
θ 1	0°	10°	12°	0°	10°	12°	
θ 2	3° BSC				3° BSC		



Ordering and Marking Information

Device Marking: 2116EJ3

Package (Available)
DFN2X5-6L-EP
Operating Temperature Range
C: -55 to 150 °C

Devices per Unit

Package	Units/	Tapes/	Units/	Inner Boxes/	Units/
Type	Tape	Inner Box	Inner Box	Carton Box	Carton Box
DFN2X5-6L-EP	3000pcs	4pcs	12000pcs	4pcs	48000pcs

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			





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